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APPLICATION NO.	FILING DATE	FIRST NAMED INVENTOR	ATTORNEY DOCKET NO.	CONFIRMATION NO.	
10/715,119	11/18/2003	Kiyohito Mukai	L8462.03118	2755	
24257	24257 7590 10/31/2005		EXAM	EXAMINER	
STEVENS DAVIS MILLER & MOSHER, LLP			DOAN, N	DOAN, NGHIA M	
1615 L STRE SUITE 850	1615 L STREET, NW SUITE 850		ART UNIT	PAPER NUMBER	
WASHINGTON, DC 20036			2825		
			DATE MAILED: 10/31/2005	DATE MAILED: 10/31/2005	

Please find below and/or attached an Office communication concerning this application or proceeding.

		Annlinetian No	Applicant(a)			
Office Action Summary		Application No.	Applicant(s)			
		10/715,119	MUKAI ET AL.			
		Examiner	Art Unit			
		Nghia M. Doan	2825			
Period fo	The MAILING DATE of this communication app or Reply	ears on the cover sheet with the c	orrespondence address			
WHIC - Exter after - If NO - Failu Any (ORTENED STATUTORY PERIOD FOR REPLY CHEVER IS LONGER, FROM THE MAILING DATE of the may be available under the provisions of 37 CFR 1.13 SIX (6) MONTHS from the mailing date of this communication. It is specified above, the maximum statutory period were to reply within the set or extended period for reply will, by statute, reply received by the Office later than three months after the mailing and patent term adjustment. See 37 CFR 1.704(b).	ATE OF THIS COMMUNICATION 36(a). In no event, however, may a reply be tirr vill apply and will expire SIX (6) MONTHS from cause the application to become ABANDONE	I. hely filed the mailing date of this communication. D (35 U.S.C. § 133).			
Status						
1)⊠	Responsive to communication(s) filed on <u>18 November 2003</u> .					
, —	This action is FINAL . 2b)⊠ This action is non-final.					
3)	Since this application is in condition for allowance except for formal matters, prosecution as to the merits is					
	closed in accordance with the practice under Ex parte Quayle, 1935 C.D. 11, 453 O.G. 213.					
Dispositi	ion of Claims					
5) <u> </u>	Claim(s) 1-17 is/are pending in the application. 4a) Of the above claim(s) is/are withdraw Claim(s) is/are allowed. Claim(s) is/are rejected. Claim(s) is/are objected to.					
8) Claim(s) <u>1-17</u> are subject to restriction and/or election requirement.						
Applicati	ion Papers					
10)	The specification is objected to by the Examine The drawing(s) filed on is/are: a) accomplicant may not request that any objection to the Replacement drawing sheet(s) including the correct The oath or declaration is objected to by the Examine	epted or b) objected to by the I drawing(s) be held in abeyance. See ion is required if the drawing(s) is ob	e 37 CFR 1.85(a). jected to. See 37 CFR 1.121(d).			
Priority (ınder 35 U.S.C. § 119					
 12) Acknowledgment is made of a claim for foreign priority under 35 U.S.C. § 119(a)-(d) or (f). a) All b) Some * c) None of: 1. Certified copies of the priority documents have been received. 2. Certified copies of the priority documents have been received in Application No. 3. Copies of the certified copies of the priority documents have been received in this National Stage application from the International Bureau (PCT Rule 17.2(a)). * See the attached detailed Office action for a list of the certified copies not received. 						
Attachmen	nt(s)					
1) Notice 2) Notice 3) Infor	ce of References Cited (PTO-892) ce of Draftsperson's Patent Drawing Review (PTO-948) mation Disclosure Statement(s) (PTO-1449 or PTO/SB/08) er No(s)/Mail Date	4) Interview Summary Paper No(s)/Mail D 5) Notice of Informal F 6) Other:				

DETAILED ACTION

1. Responsive to communication amended of application 10/715,119 filed on 11/18/2003. Claims 1-17 are pending. Upon further consideration, this application merits a restriction requirement.

Election/Restrictions

- 2. Restriction to one of the following inventions is required under 35 U.S.C. 121:
 - Claims 1-2, drawn to method inspection wires layout of a semiconductor device based on relationship between wires and contact hole, classified in class 716, subclass 4.
 - II. Claims 3 and 6-8, drawn to method inspection wires layout of a semiconductor device based on the total area of the contact holes, classified in class 716, subclass 4.
 - III. Claims 4-5 and 14-15, drawn to method inspection wires layout of a semiconductor device based on number of contact holes in the wires of the same node, classified in class 716, subclass 4.
 - IV. Claims 9-10, drawn to method inspection wires layout of a semiconductor device based on the step of calculating the number of the contact hole in the wires having a constant width, classified in class 716, subclass 4.
 - V. Claims 11-13, drawn to method inspection wires layout of a semiconductor device based on the steps of dividing the entire area of the chip layout into a plurality of inspection region associated with the wires of a constant width, classified in class 716, subclass 4.

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VI. Claims 16-17, drawn to method inspection wires layout of a semiconductor device using an antenna check, classified in class 716, subclass 4.

3. Invention groups I, II, III, IV, V, and VI are related as combination and subcombination. Inventions in this relationship are distinct if it can be shown that (1) the combination as claimed does not require the particulars of the subcombination as claimed for patentability, and (2) that the subcombination has utility by itself or in other combinations (MPEP § 806.05(c)). In the instant case, the combination as claimed does not require the particulars of the subcombination as claimed because:

Group I drawn to method inspection wires layout of a semiconductor device based on relationship between wires and contact hole;

Group IV drawn to method inspection wires layout of a semiconductor device based on the step of calculating the number of the contact hole in the wires having a constant width; and

Group V drawn to method inspection wires layout of a semiconductor device based on the steps of dividing the entire area of the chip layout into a plurality of inspection region associated with the wires of a constant width.

The subcombination has separate utility such as:

Group II drawn to method inspection wires layout of a semiconductor device based on the total area of the contact holes;

Group III drawn to method inspection wires layout of a semiconductor device based on number of contact holes in the wires of the same node; and

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Group VI drawn to method inspection wires layout of a semiconductor device using an antenna check

- 4. Because these inventions are distinct for the reasons given above and the search required for Group I through VI is distinct, restriction for examination purposes as indicated is proper.
- 5. Applicant is advised that the reply to this requirement to be complete must include an election of the invention to be examined even though the requirement be traversed (37 CFR 1.143).
- 6. Applicant is reminded that upon the cancellation of claims to a non-elected invention, the inventorship must be amended in compliance with 37 CFR 1.48(b) if one or more of the currently named inventors is no longer an inventor of at least one claim remaining in the application. Any amendment of inventorship must be accompanied by a request under 37 CFR 1.48(b) and by the fee required under 37 CFR 1.17(i).

Conclusion

Any inquiry concerning this communication or earlier communications from the examiner should be directed to Nghia M. Doan whose telephone number is 571-272-5973. The examiner can normally be reached on 8:30-5:30.

If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, Matthew Smith can be reached on 571-272-1907. The fax phone number for the organization where this application or proceeding is assigned is 571-273-8300.

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Information regarding the status of an application may be obtained from the Patent Application Information Retrieval (PAIR) system. Status information for published applications may be obtained from either Private PAIR or Public PAIR. Status information for unpublished applications is available through Private PAIR only. For more information about the PAIR system, see http://pair-direct.uspto.gov. Should you have questions on access to the Private PAIR system, contact the Electronic Business Center (EBC) at 866-217-9197 (toll-free).

Nghia M. Doan Patent Examiner AU 2825 NMD

A. M. Thompson Primary Examiner

Technology Center 2800